

JTAG Test Systems



ASSET and Agilent Technologies announce two JTAG test systems to reduce costs for electronic equipment manufacturers by moving tests developed in the design department to a high-volume manufacturing environment, eliminating the need to re-develop tests in manufacturing. The solutions merge the capabilities of an ASSET ScanWorks Manufacturing Station and the Agilent 3070 ICT system. The final configuration of the solution is determined by a number of factors, including the volume of test, the financial requirements of the user organization and the current configuration of the user's 3070 system.

ASSET InterTech, Inc.

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